Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/781,461	WEI ET AL.	
Examiner	Art Unit	
Betsy L. Deppe	2611	

	<u> </u>				
SEARCHED					
Class	Subclass	Date	Examiner		
375	147	7/30/2007	BD		
375	316	7/30/2007	BD		
375	340	7/30/2007	BD		
370	320	7/30/2007	BD		
370	335	7/30/2007	BD		
370	342	7/30/2007	BD		
370	441	-7/30/2007	· BD		
370	479	7/30/2007	BD		
455	561	7/30/2007	BD		
•					

. INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
				
	<u> </u>			
		i		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Reviewed PLUS search results	7/30/2007	BD		
Inventor name search	7/30/2007	BD		
Text search (USPAT; USPG-PUB)	7/30/2007	BD		
Text search (USPAT; USPG-PUB; EPO; JPO; DERWENT; IBM_TDB)	8/1/2007	BD		
·				